Electronic Structure Study of CaCu₃Ti₄O₁₂ by means of X-ray Raman Scattering.

Yasuhisa Tezuka^{1*}, Masaya Mikami¹, Yuto Yokouchi¹, Hojun Im¹, Takao Watanabe¹,

Shunsuke Nozawa², Nobuo Nakajima³, Toshiaki Iwazumi⁴

¹Grad. Sch. of Sci. and Tech., Hirosaki Univ., Hirosaki, Aomori 036-8561, Japan

²Photon Factory, Inst. of Mats. Struct. Sci., Tsukuba, Ibaraki 305-0801, Japan

³Grad. Sch. of Sci., Hiroshima Univ., Higashi-Hiroshima, Hiroshima 739-8526, Japan

⁴Grad. Sch. of Eng., Osaka Pref. Univ., Sakai, Osaka 599-8531, Japan

1 Introduction

A-site substituted perovskite CaCu₃Ti₄O₁₂ (CCTO) have recently attracted much attention due to their high dielectric constant ($\sim 10^{\circ}$) over a wide temperature range from 100 to 600 K [1]. The dielectric constant decreases abruptly at about 90 K in two orders without structural phase transition. To understand such anomalous dielectric behavior, electronic structure should be investigated in detail. X-ray Raman scattering (XRS) study is suitable technique to investigate such an insulator material. The XRS results have been reported on Ti K edge of Ticompounds and showed scattering by Ti 2p3d and 2p4p core-excitations where underlines show core-hole [2]. In this study, both measurements at the Ti K and Cu K absorption edge of CCTO were performed. The Ti K measurement shows similar results with Ti-compound. In this report, the Cu K measurements are described.

2 Experiment

The XRS and Cu *K* XAS experiments were performed at beamlines BL7C. X-ray emission spectra having an energy centred at the Cu $K\alpha$ fluorescence lines ($K\alpha_i$ = 8,047.78 and $K\alpha_2$ =8,027.83 eV) were observed. The spectrum changes continuously from $K\alpha$ fluorescence to XRS when the excitation energies are changed from above to below the absorption edge. The fluorescence peaks have constant emission energies, while each XRS peak has each constant loss-energy from the excitation energy (Raman shift). The energy resolution for the Cu *K* XAS and XRS measurements were about 2 and 3 eV for 8 keV photon, respectively. The polycrystalline CCTO was prepared by a solid state reaction. The single phase of samples was confirmed by X-ray diffraction pattern.

3 Results and Discussion

Figure 1 shows comparison of several spectra of CCTO. Fig. 1(a) and 1(e) show Cu 2p and 1s X-ray absorption spectra (XAS), which reflect Cu 3d and 4p density-ofstate, respectively. The spectrum (e) was plotted in relative energy in which incident photon energies were subtracted by a binding energy of Cu 1s (8979 eV), so that the zero energy roughly corresponds to Fermi energy. In the Cu K XAS spectrum, it is known that Cu 3d state is observed at the pre-edge. The XRS measurements were performed with several excitation energies in the pre-edge region and characteristic spectra were shown in the figure. Each excitation-energy is shown by arrows. The spectrum (d) is a non-resonant (normal) XRS excited far below



Fig. 1: Comparison of several spectra of CCTO. (a) Cu 2p XAS. (b), (c), (d) XRS spectra. (e) Cu K XAS.

absorption edge and shows Cu 4p state because of selection rules of light scattering. It shows similar spectrum with the Cu K XAS, then the spectrum (d), as well as (b) and (c), is plotted so that the peaks coincide with those of Cu K XAS. The spectrum (b) is resonant XRS spectra excited just below the absorption edge, where the Cu 3d absorption is observed by quadrupole transition, and shows corresponding peaks with the Cu 2p XAS spectrum. These peaks should correspond to the Cu 3d states. The assignments of the $P_1 \sim P_7$ in the figure are based upon the XRS of Ti-compounds [2]. The spectrum (c) is also a resonant XRS spectrum excited by the energy corresponding to the peak below absorption edge. Strong peaks (*) are observed in the spectrum. Such peaks are known to be observed in divalent Cu-compounds such as CuO [3]. These peaks could not be corresponded to a band structure and seem to be excitonic state. These peaks should be studied further in many-body schemes.

References

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- * tezuka@cc.hirosaki-u.ac.jp